

Search Notes

Application/Control No.

10/776,278

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

MARUYAMA ET AL.

Art Unit

1792

SEARCHED

Class	Subclass	Date	Examiner
427	64	10/6/2008	BT
427	67	10/6/2008	BT
427	427.1	10/6/2008	BT
427	427.2	10/6/2008	BT
427	427.6	10/6/2008	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
427	64	10/6/2008	BT
427	67	10/6/2008	BT
427	437.1	10/6/2008	BT
427/427.2 427/427.6		10/6/2008	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated text search using databases in EAST	10/6/2008	BT